Non-intercepting electron beam size monitor using optical diffraction radiation interference (ODRI)

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Outlook

- Importance of Non Intercepting Diagnostic
- Optical Diffraction Radiation vs Optical Diffraction Radiation Interference
- Non collinear apertures
- Experimental setup
- Results
- Horizontal polarization
- Future applications?

High Brightness Machines

312.604

297.169 281.735

266.3 250.865

235.43

219,996

204.561 189.126

173.692

158.257

142.822

111.953

96.5182

81.0835

65.6488

50.2141 34.7794

19.3447

3.91



Figure 1: Number of bunches $(Q_b = 1 nC)$ at which Si foil (300 microns) is below the stress limit $(\Delta T = 1230^\circ)$. The energy is 1 GeV.

V. Balandin, N. Golubeva

$$\overline{B} = \frac{2I}{\pi^2 \varepsilon_x \varepsilon_y} [A/(\text{m-rad})^2]$$

High density power beam can substantially damage or destroy a foil or a wire scanner

Possible alternatives are multishots devices such as Wire scanner (intercepting) and Laser wire

Optical Diffraction Radiation (ODR)

- The charge goes into the hole without touching the screen
- The electromagnetic field of the moving charge interacts with the metallic screen
- No power is deposited on the screen
- The angular distribution of the emerging radiation is affected by the beam transverse size, the angular spread and the position inside the slit
- M. Castellano, Nucl. Instrum. Methods Phys. Res., Sect. A 394, 275 (1997).

P. Karataev et al., "Beam-Size Measurement with Optical Diffraction Radiation at KEK Accelerator Test Facility", Phys. Rev. Lett. <u>93</u>, 244802 (2004)



Background noise



Mainly Synchrotron radiation, both directly coming for bending magnets and reflected from the vacuum chamber walls



E. Chiadroni et al.,

Non-intercepting electron beam transverse diagnostics with optical diffraction radiation at the DESY FLASH facility **NIM B 266 (2008) 3789–3796**

Two slits geometry (ODRI)





Point like beams with different angular spread

Possible confusion between the contribution of the angular spread and the beam dimension

Non collinear slits

The 50 µm offset between the slits is enough to avoid mixing between the contributions of angular spread and beam size



Approximations and formulas

- Perfect metal
- Filter bandwidth negligible
- Beam energy spread negligible
- Beam Gaussian both in y and y'

Slit parallelism correction (M. Castellano, E. Chiadroni, A. Cianchi, "Phase control

effects in optical diffraction radiation from a slit", Nuclear Instruments and Methods in Physics Research A 614 (2010) 163–168)

Numerical code





Misalignment between two slits (µm) 110 113

A divergence of about 320 μ rad can be estimated from a quadrupole-scan emittance measurement carried out under the same experimental conditions

A. Cianchi et al. Nonintercepting electron beam size monitor using optical diffraction radiation interference, PHYSICAL REVIEW SPECIAL TOPICS - ACCELERATORS AND BEAMS 14, 102803 (2011)



FLASH is an excellent linac for this experiment:

- High energy up to 1 GeV
- Large number of bunches (up to 30) with high charge (up to 1 nC)
- Frequency repetition 10 Hz
- Long collaboration history

Hardware evolution

New design in the mover



Old screen holder



New screen holder

Experimental Setup



Christian Wiebers (optical system) & Hans-Christian Schroeder (apochrom. Lens)

Transport to 57BYP

 Thanks to Vladimir and Nina was possible to achieve quickly a very nice beam spot with sigma about 80 µm



BUT....

Pandora

In Greek mythology Pandora was the first woman created by Zeus to punish mankind In FLASH life is here to punish the hybris of the people that want to go to the bypass line





Different wavelengths



Horizontal polarization



X polarization





Exact formula



M. Castellano, A. Cianchi, G. Orlandi, V.A. Verzilov, *Effects of diffraction and target finite size on coherent transition radiation spectra in bunch length measurements, Nuclear Instruments and Methods in Physics Research A* 435 (1999) 297-307

Scan with the 1 mm slit



•1 mm slit moved from -66 μ m to +200 μ m

To improve

- Horizontal polarization features not fully understood
- Check the impact of two completely different beam aspect ratios
- An analytic formula would be better than a MonteCarlo code

To do

- A total non intercepting emittance measurement using the quadrupole scan technique
- Compare the result with conventional quadrupole scan
- Check if it is possible to have the same result just using only two different values of the quads current

The σ matrix $\gamma x^{2} + 2\alpha x x' + \beta x'^{2} = \varepsilon = \gamma_{0} x_{0}^{2} + 2\alpha_{0} x_{0} x_{0}' + \beta_{0} x_{0}'^{2}$ $\sigma = \begin{pmatrix} \sigma_{11} & \sigma_{12} \\ \sigma_{12} & \sigma_{22} \end{pmatrix} = \varepsilon \begin{pmatrix} \beta & -\alpha \\ -\alpha & \gamma \end{pmatrix}$ $\sigma_{11}x^2 + 2\sigma_{12}xx' + \sigma_{22}x'^2 = 1$ $\sigma_1 = M \sigma_0 M^T$ $M(s_1s_2) = \begin{pmatrix} C & S \\ C' & S' \end{pmatrix}$

Multiple profile monitors

 $\sigma_{i,11} = C_i^2 \sigma_{11} + 2S_i C_i \sigma_{12} + S_i^2 \sigma_{22}$ $\sigma_{i,22} = C_i'^2 \sigma_{11} + 2C_i' S_i' \sigma_{12} + S_i'^2 \sigma_{22}$

There are 3 unknown quantities but 2 equations!
σ_{i,11} is the squared rms beam size
σ_{i,22} is the squared rms divergence
C_i and S_i are the element of the transport matrix
We need 2 measurements in 2 different position to evaluate the emittance

Future possibilities

- For emittance measurement multiple screens are required in order to estimate the beam size in at least three different locations
- With ODRI two parameters can be measured in principle in one shot, σ_v and
 - $\sigma_{y'}$
- So only two stations are required, both non intercepting, paving the way to a totally parasitic emittance measurement

Conclusion

- ODRI is in developing
- ODRI dramatically reduce or eliminate the problem of background
- Asymmetric configuration resolves parameters ambiguities
- New measurements are foreseen to make a totally non intercepting emittance measurement

Thank you for your attention



Importance of side peaks



